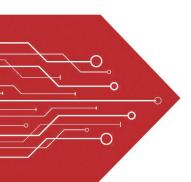
## MSKSEMI















**ESD** 

TVS

**TSS** 

MOV

**GDT** 

**PLED** 

# Broduct data sheet



**SOT - 23** 



- 1. BASE
- 2. EMITTER
- 3. COLLECTOR

#### TRANSISTOR (PNP)

#### **FEATURES**

- **High Collector Current**
- Complementary To
- S9013-MS

**MARKING: 2T1** 

#### MAXIMUM RATINGS (T<sub>a</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Value	Unit
V <sub>CBO</sub>	Collector-Base Voltage	-40	V
V <sub>CEO</sub>	Collector-Emitter Voltage	-25	V
V <sub>EBO</sub>	Emitter-Base Voltage	-5	V
Ic	Collector Current	-500	mA
Pc	Collector Power Dissipation	300	mW
R <sub>OJA</sub>	Thermal Resistance From Junction To Ambient	416	°C/W
T <sub>J</sub> ,T <sub>stg</sub>	Operation Junction and Storage Temperature Range	-55~+150	ᢗ

#### **ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)**

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V <sub>(BR)CBO</sub>	I <sub>C</sub> =-0.1mA, I <sub>E</sub> =0	-40			V
Collector-emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> =-1mA, I <sub>B</sub> =0	-25			V
Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> =-0.1mA, I <sub>C</sub> =0	-5			V
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> =-40V, I <sub>E</sub> =0			-0.1	uA
Collector cut-off current	I <sub>CEO</sub>	V <sub>CE</sub> =-20V, I <sub>B</sub> =0			-0.1	uA
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> =-5V, I <sub>C</sub> =0			-0.1	uA
DC current gain	h <sub>FE</sub>	V <sub>CE</sub> =-1V, I <sub>C</sub> =-50mA	120		400	
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> =-500mA, I <sub>B</sub> =-50mA			-0.6	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	I <sub>C</sub> =-500mA, I <sub>B</sub> =-50mA			-1.2	V
Transition frequency	f⊤	V <sub>CE</sub> =-6V,I <sub>C</sub> =-20mA, f=30MHz	150			MHz
Collector output capacitance	C <sub>ob</sub>	V <sub>CB</sub> =-10V, I <sub>E</sub> =0, f=1MHz			5	pF

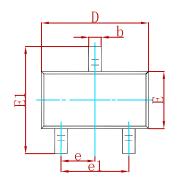
#### **CLASSIFICATION OF h**<sub>FE</sub>

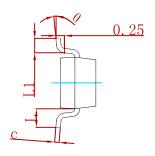
RANK	L	Н	J
RANGE	120-200	200-350	300-400

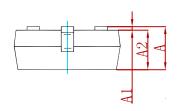




#### **PACKAGE MECHANICAL DATA**

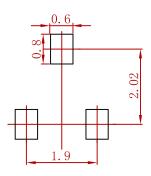






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

### **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
S9012-MS	SOT-23	3000



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